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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

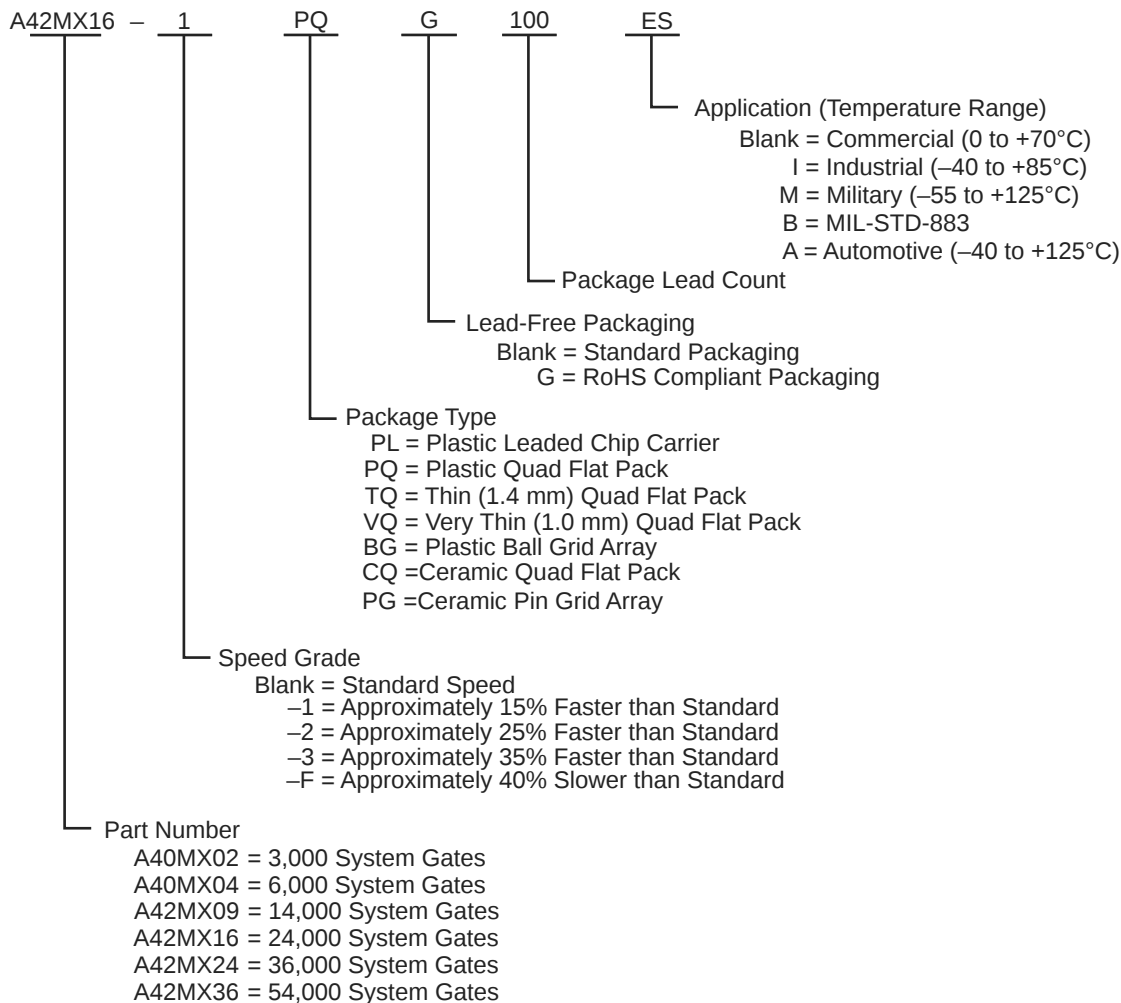
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	72
Number of Gates	36000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx24-1plg84m

2.3



The following figure shows ordering information. All the following tables show plastic and ceramic device resources, temperature and speed grade offerings.

Figure 1 •



Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the *.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the *AC225: Programming Antifuse Devices* application note and the *Silicon Sculptor 3 Programmers User Guide*.

3.3.4

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

Table 6 • 

					
40MX	5.0 V	—	—	5.5 V	5.0 V
	3.3 V	—	—	3.6 V	3.3 V
42MX	—	5.0 V	5.0 V	5.5 V	5.0 V
	—	3.3 V	3.3 V	3.6 V	3.3 V
	—	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the *AC291: 42MX Family Devices Power-Up Behavior*.

3.3.5

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

3.3.6

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

3.4.9

The JTAG test logic circuit is activated in the Designer software by selecting  . This brings up the Device Selection dialog box as shown in the following figure. The JTAG test logic circuit can be enabled by clicking the “Reserve JTAG Pins” check box. The following table explains the pins' behavior in either mode.

Figure 15 • 

Table 11 • 

	
TCK	BST input; must be terminated to logical HIGH or LOW to avoid floating User I/O
TDI, TMS	BST input; may float or be tied to HIGH User I/O
TDO	BST output; may float or be connected to TDI of another device User I/O

3.4.10

An active reset (TRST) pin is not supported; however, MX devices contain power-on circuitry that resets the boundary scan circuitry upon power-up. Also, the TMS pin is equipped with an internal pull-up resistor. This allows the TAP controller to remain in or return to the Test-Logic-Reset state when there is no input or when a logical 1 is on the TMS pin. To reset the controller, TMS must be HIGH for at least five TCK cycles.

3.4.11

Conforming to the IEEE Standard 1149.1 requires that the operation of the various JTAG components be documented. The BSDL file provides the standard format to describe the JTAG components that can be used by automatic test equipment software. The file includes the instructions that are supported, instruction bit pattern, and the boundary-scan chain order. For an in-depth discussion on BSDL files, see the *BSDL Files Format Description* application note.

BSDL files are grouped into two categories - generic and device-specific. The generic files assign all user I/Os as inouts. Device-specific files assign user I/Os as inputs, outputs or inouts.

Generic files for MX devices are available on the Microsemi SoC Product Group's website:

<http://www.microsemi.com/soc/techdocs/models/bsdl.html>.

3.5

The MX family of FPGAs is fully supported by Libero® Integrated Design Environment (IDE). Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes SynplifyPro from Synopsys, ModelSim® HDL Simulator from Mentor Graphics® and Viewdraw.

Libero IDE includes place-and-route and provides a comprehensive suite of backend support tools for FPGA development, including timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor.

3.9.1 3.3V

Table 22 • 3.3V

		IBIS Model								
Symbol	Parameter	Min	Typ	Max	Min	Max	Min	Max	Units	
VOH ¹	IOH = –10 mA	2.4		2.4					V	
	IOH = –4 mA					2.4		2.4	V	
VOL ¹	IOL = 10 mA	0.5		0.5					V	
	IOL = 6 mA					0.4		0.4	V	
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH ²		2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	V
IL	VIN = 0.5 V	–10		–10		–10		–10		μA
IH	VIN = 2.7 V	–10		–10		–10		–10		μA
Input Transition Time, T _R and T _F		500		500		500		500		ns
C _{IO} I/O Capacitance		10		10		10		10		pF
Standby Current, ICC ³	A42MX09	5		25		25		25		mA
	A42MX16	6		25		25		25		mA
	A42MX24, A42MX36	20		25		25		25		mA
Low Power Mode Standby Current		0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0		mA
I/O I/O source/sink current Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)										

1. Only one output tested at a time. VCCI = min.

2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

3. All outputs unloaded. All inputs = VCCI or GND

3.9.2 5.0V

MX PCI device I/O drivers were designed specifically for high-performance PCI systems. Figure 16, page 28 shows the typical output drive characteristics of the MX devices. MX output drivers are compliant with the PCI Local Bus Specification.

Table 23 • 5.0V

Symbol		P				M		Units
		Min	Max	Min	Max			
VCCI	Supply Voltage for I/Os			4.75	5.25	4.75	5.25 ²	V
VIH ³	Input High Voltage			2.0	VCC + 0.5	2.0	VCCI + 0.3	V
VIL	Input Low Voltage			−0.5	0.8	−0.3	0.8	V
IIH	Input High Leakage Current	VIN = 2.7 V			70	—	10	μA
IIL	Input Low Leakage Current	VIN=0.5 V			−70	—	−10	μA
VOH	Output High Voltage	IOUT = −2 mA IOUT = −6 mA		2.4		3.84		V
VOL	Output Low Voltage	IOUT = 3 mA, 6 mA			0.55	—	0.33	V

Table 34 • **40MX and 42MX FPGAs**
(V_{DD} = 1.0 V)
(V_{DD} = 4.75 V/T)

(continued)
T_J = 70°C

		3 2 1 0 0 0 0										
		M M M M M M M M										
t _{INYH}	Pad-to-Y HIGH	0.7		0.8		0.9		1.1		1.5	ns	
t _{INYL}	Pad-to-Y LOW	0.6		0.7		0.8		1.0		1.3	ns	
		1										
t _{IRD1}	FO = 1 Routing Delay	2.1		2.4		2.2		3.2		4.5	ns	
t _{IRD2}	FO = 2 Routing Delay	2.6		3.0		3.4		4.0		5.6	ns	
t _{IRD3}	FO = 3 Routing Delay	3.1		3.6		4.1		4.8		6.7	ns	
t _{IRD4}	FO = 4 Routing Delay	3.6		4.2		4.8		5.6		7.8	ns	
t _{IRD8}	FO = 8 Routing Delay	5.7		6.6		7.5		8.8		12.4	ns	
t _{CKH}	Input Low to HIGH	FO = 16	4.6		5.3		6.0		7.0		9.8	ns
		FO = 128	4.6		5.3		6.0		7.0		9.8	
t _{CKL}	Input High to LOW	FO = 16	4.8		5.6		6.3		7.4		10.4	ns
		FO = 128	4.8		5.6		6.3		7.4		10.4	
t _{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2	2.6		2.9		3.4		4.8		ns
		FO = 128	2.4	2.7		3.1		3.6		5.1		
t _{PWL}	Minimum Pulse Width LOW	FO = 16	2.2	2.6		2.9		3.4		4.8		ns
		FO = 128	2.4	2.7		3.01		3.6		5.1		
t _{CKSW}	Maximum Skew	FO = 16	0.4		0.5		0.5		0.6		0.8	ns
		FO = 128	0.5		0.6		0.7		0.8		1.2	
t _P	Minimum Period	FO = 16	4.7	5.4		6.1		7.2		10.0		ns
		FO = 128	4.8	5.6		6.3		7.5		10.4		
f _{MAX}	Maximum Frequency	FO = 16	188		175		160		139		83	MHz
		FO = 128	181		168		154		134		80	

Table 36 • **40MX and 42MX FPGAs**
DC 4.75 V_T

J = 70°C

(continued)

Symbol	Description	Temperature (°C)						Units
		30	25	15	0	40	75	
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0	0.0	0.0	0.0	ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.8	4.3	5.0	7.0	ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	3.3		3.8	4.3	5.0	7.0	ns
t _A	Flip-Flop Clock Input Period	4.8		5.6	6.3	7.5	10.4	ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		181	167	154	134	80	MHz
Routing								
t _{INYH}	Pad-to-Y HIGH		0.7	0.8	0.9	1.1	1.5	ns
t _{INYL}	Pad-to-Y LOW		0.6	0.7	0.8	1.0	1.3	ns
Routing Delay								
t _{IRD1}	FO = 1 Routing Delay		2.1	2.4	2.2	3.2	4.5	ns
t _{IRD2}	FO = 2 Routing Delay		2.6	3.0	3.4	4.0	5.6	ns
t _{IRD3}	FO = 3 Routing Delay		3.1	3.6	4.1	4.8	6.7	ns
t _{IRD4}	FO = 4 Routing Delay		3.6	4.2	4.8	5.6	7.8	ns
t _{IRD8}	FO = 8 Routing Delay		5.7	6.6	7.5	8.8	12.4	ns
Setup and Hold Times								
t _{CKH}	Input Low to HIGH	FO = 16	4.6	5.3	6.0	7.0	9.8	ns
		FO = 128	4.6	5.3	6.0	7.0	9.8	
t _{CKL}	Input High to LOW	FO = 16	4.8	5.6	6.3	7.4	10.4	ns
		FO = 128	4.8	5.6	6.3	7.4	10.4	
t _{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2	2.6	2.9	3.4	4.8	ns
		FO = 128	2.4	2.7	3.1	3.6	5.1	
t _{PWL}	Minimum Pulse Width LOW	FO = 16	2.2	2.6	2.9	3.4	4.8	ns
		FO = 128	2.4	2.7	3.01	3.6	5.1	
t _{CKSW}	Maximum Skew	FO = 16	0.4	0.5	0.5	0.6	0.8	ns
		FO = 128	0.5	0.6	0.7	0.8	1.2	
t _P	Minimum Period	FO = 16	4.7	5.4	6.1	7.2	10.0	ns
		FO = 128	4.8	5.6	6.3	7.5	10.4	
f _{MAX}	Maximum Frequency	FO = 16	188	175	160	139	83	MHz
		FO = 128	181	168	154	134	80	
Enable Times								
t _{DLH}	Data-to-Pad HIGH		3.3	3.8	4.3	5.1	7.2	ns
t _{DHL}	Data-to-Pad LOW		4.0	4.6	5.2	6.1	8.6	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7	4.3	4.9	5.8	8.0	ns
t _{ENZL}	Enable Pad Z to LOW		4.7	5.4	6.1	7.2	10.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.9	9.1	10.4	12.2	17.1	ns

Table 39 • A2M5 UN1.3 V_{DD}
3.0 V_T

$T_J = 70^\circ\text{C}$

(continued)

		3 2 1 0					
5							
t _{DLH}	Data-to-Pad HIGH	3.4	3.8	5.5	6.4	9.0	ns
t _{DHL}	Data-to-Pad LOW	4.1	4.5	4.2	5.0	7.0	ns
t _{ENZH}	Enable Pad Z to HIGH	3.7	4.1	4.6	5.5	7.6	ns
t _{ENZL}	Enable Pad Z to LOW	4.1	4.5	5.1	6.1	8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z	6.9	7.6	8.6	10.2	14.2	ns
t _{ENLZ}	Enable Pad LOW to Z	7.5	8.3	9.4	11.1	15.5	ns
t _{GLH}	G-to-Pad HIGH	5.8	6.5	7.3	8.6	12.0	ns
t _{GHL}	G-to-Pad LOW	5.8	6.5	7.3	8.6	12.0	ns
t _{LSU}	I/O Latch Set-Up	0.7	0.8	0.9	1.0	1.4	ns
t _{LH}	I/O Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading	8.7	9.7	10.9	12.9	18.0	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading	12.2	13.5	15.4	18.1	25.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH	0.04	0.04	0.05	0.06	0.08	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW	0.05	0.05	0.06	0.07	0.10	ns/pF

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 40 • A2M5 UN1.0 V_{DD}
4.75 V_T

$T_J = 70^\circ\text{C}$

		3 β 2 β 1 β 0 β					
Symbol		M M M M	M M M M	M M M M			Units
1							
t _{PD1}	Single Module	1.4	1.5	1.7	2.0	2.8	ns
t _{CO}	Sequential Clock-to-Q	1.4	1.6	1.8	2.1	3.0	ns
t _{GO}	Latch G-to-Q	1.4	1.5	1.7	2.0	2.8	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q	1.6	1.7	2.0	2.3	3.3	ns
2							
t _{RD1}	FO = 1 Routing Delay	0.8	0.9	1.0	1.2	1.6	ns
t _{RD2}	FO = 2 Routing Delay	1.0	1.2	1.3	1.5	2.1	ns

**Table 41 • 4216 12.3 V
52 3.0 VT**

$\lambda_1 = 70\text{€}$

(continued)

Parameter		3.3V 2.5V 1.8V 1.5V						
		Minimum		Maximum		Typical		Unit
t _{PWL}	Minimum Pulse Width LOW	FO = 32 FO = 384	5.3 6.2	5.9 6.9	6.7 7.9	7.8 9.2	11.0 12.9	ns ns
t _{CKSW}	Maximum Skew	FO = 32 FO = 384	0.5 2.2	0.5 2.4	0.6 2.7	0.7 3.2	1.0 4.5	ns ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32 FO = 384	0.0 0.0	0.0 0.0	0.0 0.0	0.0 0.0	0.0 0.0	ns ns
t _{HEXT}	Input Latch External Hold	FO = 32 FO = 384	3.9 4.5	4.3 4.9	4.9 5.6	5.7 6.6	8.0 9.2	ns ns
t _P	Minimum Period	FO = 32 FO = 384	7.0 7.7	7.8 8.6	8.4 9.3	9.7 10.7	16.2 17.8	ns ns
f _{MAX}	Maximum Frequency	FO = 32 FO = 384	142 129	129 117	119 108	103 94	62 56	MHz MHz
5								
t _{DLH}	Data-to-Pad HIGH		3.5	3.9	4.4	5.2	7.3	ns
t _{DHL}	Data-to-Pad LOW		4.1	4.6	5.2	6.1	8.6	ns
t _{ENZH}	Enable Pad Z to HIGH		3.8	4.2	4.8	5.6	7.8	ns
t _{ENZL}	Enable Pad Z to LOW		4.2	4.6	5.3	6.2	8.7	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.6	8.4	9.5	11.2	15.7	ns
t _{ENLZ}	Enable Pad LOW to Z		7.0	7.8	8.8	10.4	14.5	ns
t _{GLH}	G-to-Pad HIGH		4.8	5.3	6.0	7.2	10.0	ns
t _{GHL}	G-to-Pad LOW		4.8	5.3	6.0	7.2	10.0	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0	8.9	10.1	11.9	16.7	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		11.3	12.5	14.2	16.7	23.3	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.04	0.04	0.05	0.06	0.08	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.05	0.05	0.06	0.07	0.10	ns/pF
5								
t _{DLH}	Data-to-Pad HIGH		4.5	5.0	5.6	6.6	9.3	ns
t _{DHL}	Data-to-Pad LOW		3.4	3.8	4.3	5.1	7.1	ns
t _{ENZH}	Enable Pad Z to HIGH		3.8	4.2	4.8	5.6	7.8	ns
t _{ENZL}	Enable Pad Z to LOW		4.2	4.6	5.3	6.2	8.7	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.6	8.4	9.5	11.2	15.7	ns
t _{ENLZ}	Enable Pad LOW to Z		7.0	7.8	8.8	10.4	14.5	ns
t _{GLH}	G-to-Pad HIGH		7.1	7.9	8.9	10.5	14.7	ns
t _{GHL}	G-to-Pad LOW		7.1	7.9	8.9	10.5	14.7	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0	8.9	10.1	11.9	16.7	ns

		3 2 1 0						
		MM	MM	MM	MM			
t _{DLH}	Data-to-Pad HIGH	2.4	2.7	3.1	3.6	5.1	ns	
t _{DHL}	Data-to-Pad LOW	2.8	3.2	3.6	4.2	5.9	ns	
t _{ENZH}	Enable Pad Z to HIGH	2.5	2.8	3.2	3.8	5.3	ns	
t _{ENZL}	Enable Pad Z to LOW	2.8	3.1	3.5	4.2	5.9	ns	
t _{ENHZ}	Enable Pad HIGH to Z	5.2	5.7	6.5	7.6	10.7	ns	
t _{ENLZ}	Enable Pad LOW to Z	4.8	5.3	6.0	7.1	9.9	ns	
t _{GLH}	G-to-Pad HIGH	2.9	3.2	3.6	4.3	6.0	ns	
t _{GHL}	G-to-Pad LOW	2.9	3.2	3.6	4.3	6.0	ns	
t _{LSU}	I/O Latch Output Set-Up	0.5	0.5	0.6	0.7	1.0	ns	
t _{LH}	I/O Latch Output Hold	0.0	0.0	0.0	0.0	0.0	ns	
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O	5.6	6.1	6.9	8.1	11.4	ns	
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O	10.6	11.8	13.4	15.7	22.0	ns	
d _{TLH}	Capacitive Loading, LOW to HIGH	0.04	0.04	0.04	0.05	0.07	ns/pF	
d _{THL}	Capacitive Loading, HIGH to LOW	0.03	0.03	0.03	0.04	0.06	ns/pF	

Table 44 • A2B6 15.0 V_{DD}
4.75 V_T $T_J = 70^\circ\text{C}$

		3 2 1 0 0 0					
5							
t _{DLH}	Data-to-Pad HIGH	3.5	3.9	4.5	5.2	7.3	ns
t _{DHL}	Data-to-Pad LOW	2.5	2.7	3.1	3.6	5.1	ns
t _{ENZH}	Enable Pad Z to HIGH	2.7	3.0	3.3	3.9	5.5	ns
t _{ENZL}	Enable Pad Z to LOW	2.9	3.3	3.7	4.3	6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z	5.3	5.8	6.6	7.8	10.9	ns
t _{ENLZ}	Enable Pad LOW to Z	4.9	5.5	6.2	7.3	10.2	ns
t _{GLH}	G-to-Pad HIGH	5.0	5.6	6.3	7.5	10.4	ns
t _{GHL}	G-to-Pad LOW	5.0	5.6	6.3	7.5	10.4	ns
t _{LSU}	I/O Latch Set-Up	0.5	0.5	0.6	0.7	1.0	ns
t _{LH}	I/O Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O	5.7	6.3	7.1	8.4	11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O	7.8	8.6	9.8	11.5	16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH	0.07	0.08	0.09	0.10	0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW	0.07	0.08	0.09	0.10	0.14	ns/pF

- For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
- Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
- Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
- Delays based on 35 pF loading.

Table 45 • A2B6 15.3 V_{DD}
3.0 V_T $T_J = 70^\circ\text{C}$

		3 2 1 0					

Table 45 • 42MX (continued)
3.0 V_T **(T_J = 70°C)**

Symbol	Description	3 2 1 0					Unit
		ns	ns	ns	ns	ns	
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O	10.9	12.1	13.7	16.1	22.5	ns
d _{TLH}	Capacitive Loading, LOW to HIGH	0.10	0.11	0.12	0.14	0.20	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW	0.10	0.11	0.12	0.14	0.20	ns/pF
5							
t _{DLH}	Data-to-Pad HIGH	4.9	5.5	6.2	7.3	10.3	ns
t _{DHL}	Data-to-Pad LOW	3.4	3.8	4.3	5.1	7.1	ns
t _{ENZH}	Enable Pad Z to HIGH	3.7	4.1	4.7	5.5	7.7	ns
t _{ENZL}	Enable Pad Z to LOW	4.1	4.6	5.2	6.1	8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z	7.4	8.2	9.3	10.9	15.3	ns
t _{ENLZ}	Enable Pad LOW to Z	6.9	7.6	8.7	10.2	14.3	ns
t _{GLH}	G-to-Pad HIGH	7.0	7.8	8.9	10.4	14.6	ns
t _{GHL}	G-to-Pad LOW	7.0	7.8	8.9	10.4	14.6	ns
t _{LSU}	I/O Latch Set-Up	0.7	0.7	0.8	1.0	1.4	ns
t _{LH}	I/O Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O	7.9	8.8	10.0	11.8	16.5	ns

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

3.12

This section lists the pin descriptions for 40MX and 42MX series FPGAs.

CLK

Clock inputs for clock distribution networks. CLK is for 40MX while CLKA and CLKB are for 42MX devices. The clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

V_{SS}

Input LOW supply voltage.

V_{CC}

Table 51 • Q44

Q44	
Pin	Assignment
43	I/O
44	GNDQ
45	GNDI
46	NC
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	VCC
55	VCCI
56	NC
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	GND
65	GNDI
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	SDO
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	GNDQ

Table 51 • Q144

Q144	
Pin	Assignment
80	GNDI
81	NC
82	I/O
83	I/O
84	I/O
85	I/O
86	I/O
87	I/O
88	VKS
89	VPP
90	VCC
91	VCCI
92	NC
93	VSV
94	I/O
95	I/O
96	I/O
97	I/O
98	I/O
99	I/O
100	GND
101	GNDI
102	NC
103	I/O
104	I/O
105	I/O
106	I/O
107	I/O
108	I/O
109	I/O
110	SDI
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	GNDQ

Table 57 • **Q76**

Q76			
Pin	A2M9 5	A2M6 5	A2M4 5
47		I/O	I/O
48		I/O	I/O
49		I/O	WD, I/O
50		I/O	WD, I/O
51		I/O	I/O
52		NC	VCCI
53		I/O	I/O
54		NC	I/O
55		NC	WD, I/O
56		I/O	WD, I/O
57		NC	I/O
58		I/O	I/O
59		I/O	WD, I/O
60		I/O	WD, I/O
61		NC	I/O
62		I/O	I/O
63		I/O	I/O
64		NC	I/O
65		I/O	I/O
66		NC	I/O
67		GND	GND
68		VCCA	VCCA
69		I/O	WD, I/O
70		I/O	WD, I/O
71		I/O	I/O
72		I/O	I/O
73		I/O	I/O
74		NC	I/O
75		I/O	I/O
76		I/O	I/O
77		NC	WD, I/O
78		NC	WD, I/O
79		I/O	I/O
80		NC	I/O
81		I/O	I/O
82		NC	VCCI
83		I/O	I/O

Table 58 • Q08

Q08		
Pin	Q08	Pin
1	GND	
2	VCCA	
3	MODE	
4	I/O	
5	I/O	
6	I/O	
7	I/O	
8	I/O	
9	I/O	
10	I/O	
11	I/O	
12	I/O	
13	I/O	
14	I/O	
15	I/O	
16	I/O	
17	VCCA	
18	I/O	
19	I/O	
20	I/O	
21	I/O	
22	GND	
23	I/O	
24	I/O	
25	I/O	
26	I/O	
27	GND	
28	VCCI	
29	VCCA	
30	I/O	
31	I/O	
32	VCCA	
33	I/O	
34	I/O	
35	I/O	
36	I/O	

Table 58 • Q08

Q08	
Pin	Assignment
148	I/O
149	I/O
150	GND
151	I/O
152	I/O
153	I/O
154	I/O
155	I/O
156	I/O
157	GND
158	I/O
159	SDI, I/O
160	I/O
161	WD, I/O
162	WD, I/O
163	I/O
164	VCCI
165	I/O
166	I/O
167	I/O
168	WD, I/O
169	WD, I/O
170	I/O
171	QCLKD, I/O
172	I/O
173	I/O
174	I/O
175	I/O
176	WD, I/O
177	WD, I/O
178	PRA, I/O
179	I/O
180	CLKA, I/O
181	I/O
182	VCCI
183	VCCA
184	GND

Table 58 • Q08

Q08	
Pin	Assignment
185	I/O
186	CLKB, I/O
187	I/O
188	PRB, I/O
189	I/O
190	WD, I/O
191	WD, I/O
192	I/O
193	I/O
194	WD, I/O
195	WD, I/O
196	QCLKC, I/O
197	I/O
198	I/O
199	I/O
200	I/O
201	I/O
202	VCCI
203	WD, I/O
204	WD, I/O
205	I/O
206	I/O
207	DCLK, I/O
208	I/O

Table 59 • Q56

Q56		
Pin	Q56	Pin
59	I/O	
60	VCCA	
61	GND	
62	GND	
63	NC	
64	NC	
65	NC	
66	I/O	
67	SDO, TDO, I/O	
68	I/O	
69	WD, I/O	
70	WD, I/O	
71	I/O	
72	VCCI	
73	I/O	
74	I/O	
75	I/O	
76	WD, I/O	
77	GND	
78	WD, I/O	
79	I/O	
80	QCLKB, I/O	
81	I/O	
82	I/O	
83	I/O	
84	I/O	
85	I/O	
86	I/O	
87	WD, I/O	
88	WD, I/O	
89	I/O	
90	I/O	
91	I/O	
92	I/O	
93	I/O	
94	I/O	
95	VCCI	

Table 59 • Q56

Q56	
Pin	Assignment
244	WD, I/O
245	I/O
246	I/O
247	I/O
248	VCCI
249	I/O
250	WD, I/O
251	WD, I/O
252	I/O
253	SDI, I/O
254	I/O
255	GND
256	NC

Figure 51 • B72

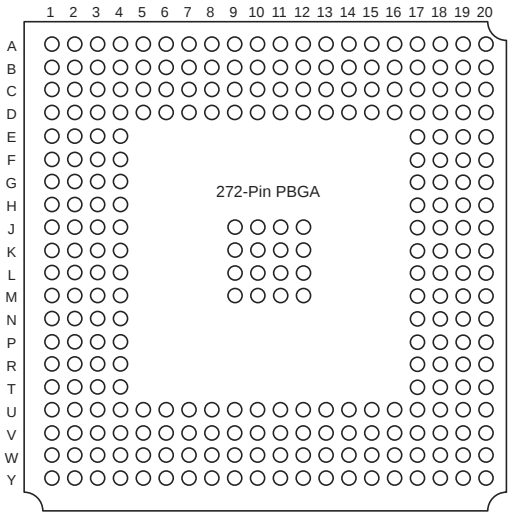


Table 60 • B72

B72	
Pin	Assignment
A1	GND
A2	GND
A3	I/O
A4	WD, I/O
A5	I/O

Table 60 • B72

B72	
Pin A2B5	
J9	GND
J10	GND
J11	GND
J12	GND
J17	VCCA
J18	I/O
J19	I/O
J20	I/O
K1	I/O
K2	I/O
K3	I/O
K4	VCCI
K9	GND
K10	GND
K11	GND
K12	GND
K17	I/O
K18	VCCA
K19	VCCA
K20	LP
L1	I/O
L2	I/O
L3	VCCA
L4	VCCA
L9	GND
L10	GND
L11	GND
L12	GND
L17	VCCI
L18	I/O
L19	I/O
L20	TCK, I/O
M1	I/O
M2	I/O
M3	I/O
M4	VCCI
M9	GND